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Serial No.: 09/1730,246

Applicant(s): JATHAN D. EDWARDS

Filing Date: December 5, 2000

Technology Center 2600  
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Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Appropriate Date If
	5,516,469	05/96	Santoh et al.			
	5,576,918	11/96	Bar-Gadda et al.			
	5,626,941	05/97	Quano			
	5,723,033	03/98	Weiss			
	5,739,972	04/98	Smith et al.			
	5,751,510	05/98	Smith et al.			
	5,889,756	03/99	Ichihara et al.			
	6,190,838	02/01	Kerfeld			

Document Number	Date	Country	Class	Sub-Class	Translation	Yes	No
97097452	04/97	Japan				X	
97138981	05/97	Japan				X	
WO 00/48172	08/00	WIPO					

OTHER DOCUMENTS (Including Authors, Title, Date, Pertinent Papers, etc.)							

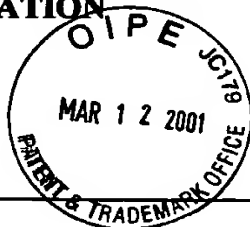
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**U.S. PATENT DOCUMENTS**

Examiner Initial	Document Number	Date	Name	Class	Sub-Class	Filing Date If Appropriate
WR	4,150,398	04/79	Kojima et al.			
WR	4,304,806	12/81	Anderson et al.			
WR	4,308,337	12/81	Roach et al.			
WR	4,374,077	02/83	Kerfeld			
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WR	4,650,735	03/87	De Last			
WR	5,096,563	03/92	Yoshizawa et al.			
WR	5,149,607	09/92	De Graaf et al.			

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date	Country	Class	Sub-Class	Translation	
						Yes	No
WR	0 444 367 A1	09/91	European Pat. Office				
WR	2-10536	01/90	Japan			X	
WR	2-244440	09/90	Japan			X	
WR	DE 41 40 712 A1	10/92	Germany			Abstract Only	
WR	6-60441	03/94	Japan			X	
WR	8-147768	06/96	Japan			X	

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WR	F. Dill et al., "Characterization of Postive Photoresist," IEEE Transactions on Electron Devices, Vol. ED-22, No. 7, July 1975, pp. 445-452
WR	E. O. Keiser, "VideoDisc Mastering," RCA Review, Vol. 39, No. 1, March 1978, pp. 60-86
WR	P. Trefonas III et al., "New Principle for Image Enhancement in Single Layer Positive Photoresists," SPIE Vol. 771, <i>Advances in Resist Technology and Processing IV</i> , March 1987, pp. 194-210
WR	S. Nakamura et al., "High Density Recording for Magneto-optical Disk Drive," IEEE Transactions on Magnetics, Vol. 34, No. 2, March 1998, pp. 411-413

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